



4th Workshop on Remote Sensing and Modeling of Surface Properties

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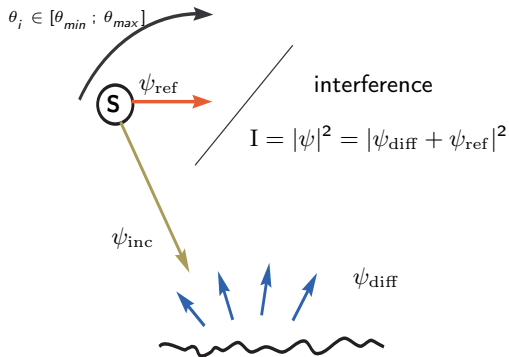
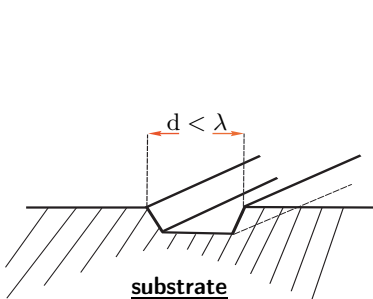
Reconstruction of surface profiles by iterative Newton-Kantorovitch's method

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S. Arhab¹, M. JOELSON¹ and G. SORIANO²

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1. Université d'Avignon, INRA, EMMAH (UMR 1114)
 2. Université Aix-Marseille, Institut Fresnel (UMR 7249)

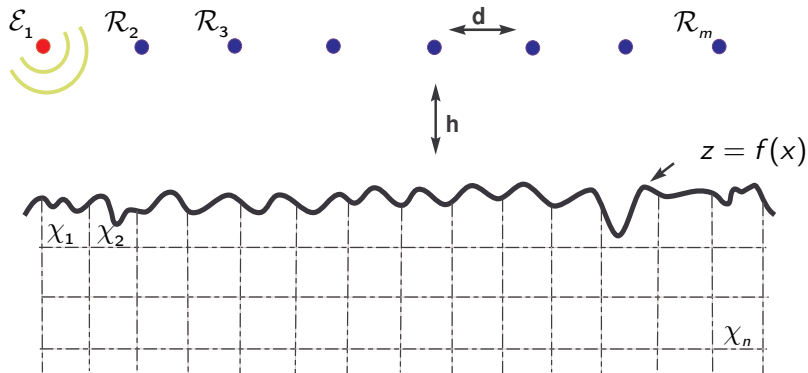
- 1 Two configurations for two applications
- 2 Position of the problem
- 3 Newton-Kantorovitch's method
- 4 Results



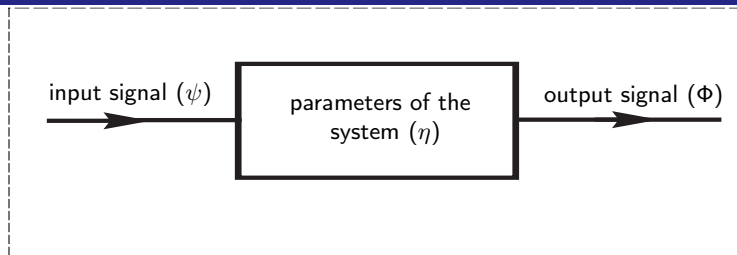
Objective : characterize surface roughness with lateral resolution beyond the Rayleigh criterion

- Two configurations for two applications

- Infer soil moisture and surface roughness



$\eta = \{f, \chi\}$. for a known contrast, $\eta = f$



$$\left\{ \begin{array}{l} \psi \in \mathcal{E}, \text{ space of the input signal} \\ \Phi \in \Sigma, \text{ space of the output signal} \\ \eta \in \Gamma, \text{ parameter space of the system} \end{array} \right.$$

$\mathbf{F}(\eta)$ an operator that depends on the parameter η , such as : $\Phi = \mathbf{F}(\eta) \psi$

in general ψ is well known, is noted for brevity : $\Phi = \mathbf{F}(\eta)$

Example (TE ; Dirichlet).

Observation equation

$$\Phi(\theta, \theta_i) \propto - \int_{\Gamma} \partial_n \psi(x, \eta(x), \theta_i) e^{-i(k_x(\theta)x + k_z(\theta)\eta(x))} d\Gamma$$

State equation

$$\psi_{\text{inc}}(x', \eta(x'), \theta_i) = \int_{\Gamma} g(x, \eta(x), x', \eta(x')) \partial_n \psi(x, \eta(x), \theta_i) d\Gamma$$

$g(x, \eta(x), x', \eta(x')) = \frac{i}{4} H_0^1(k\sqrt{(x-x')^2 + (\eta(x) - \eta(x'))^2})$: free space Green's function.

- Solving the forward problem is to :

$$\text{For } \eta \in \Gamma, \text{ we calculate : } \Phi = \mathbf{F}(\eta)$$

- Solving the inverse problem is to :

$$\text{For } \Phi \in \Sigma, \text{ we calculate : } \eta = \mathbf{F}^{-1}(\Phi)$$

- Note : This inverse problem is difficult to solve because it is ill-posed, meaning , it does not satisfy at least one of the three Hadamard's criteria, defined for a well-posed problem :
 - existence of the solution
 - uniqueness of the solution
 - continuity of the solution against data

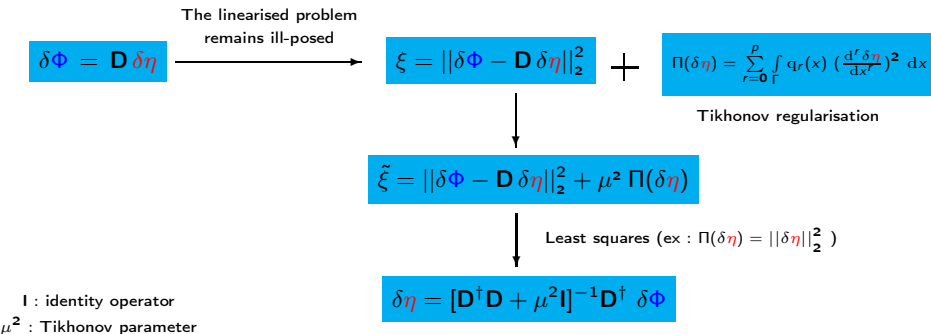
+ nonlinearity of $\mathbf{F}!!!$

Fréchet's Operator

Definition : Newton-Kantorovich's method is to find the Fréchet's operator \mathbf{D} , that linearise locally (in the vicinity of η) the nonlinear operator \mathbf{F} :

$$\mathbf{F}(\eta + \delta\eta) = \mathbf{F}(\eta) + \mathbf{D}\delta\eta + o(\|\delta\eta\|_2), \text{ lorsque } \|\delta\eta\|_2 \rightarrow \mathbf{0}$$

$$\mathbf{F}(\eta + \delta\eta) - \mathbf{F}(\eta) = \delta\Phi \simeq \mathbf{D}\delta\eta$$



Organigram of the inversion algorithm

 ϕ^{mes} : measured data η_0 : initial guess η_n

$$\phi_n = F_n(\eta_n)$$

 η_n : best solution
of the problem

if yes

 $n = n + 1$

$$\mathcal{F}_n = \frac{\|\phi^{\text{mes}} - \phi_n\|_2^2}{\|\phi^{\text{mes}}\|_2^2} \leq \tau ?$$

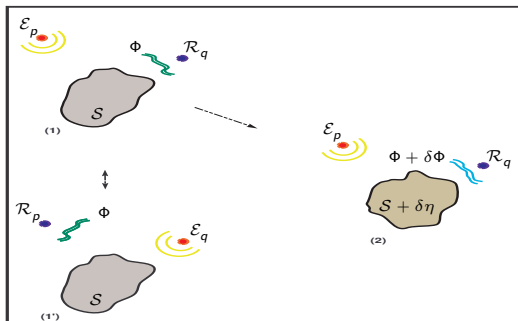
otherwise

$$\eta_{n+1} = \eta_n + [D_n^\dagger D_n + \mu^2 I]^{-1} D_n^\dagger (\phi^{\text{mes}} - \phi_n)$$

For a small change $\delta\eta$ in the surface S , what change $\delta\Phi$ in the scattered field?



The Fréchet's operator \mathbf{D} stands as a linear relationship between $\delta\eta$ and $\delta\Phi$, such as : $\delta\Phi = \mathbf{D} \delta\eta$



surface profile (perfectly conducting object),

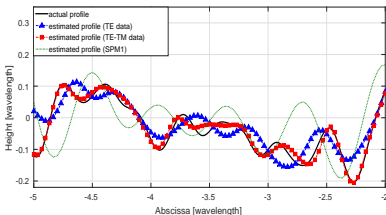
$$\delta\Phi \propto \int_S [k^2 \mathbf{J}_{(1)} \cdot \mathbf{J}_{(1')} - (\nabla_s \cdot \mathbf{J}_{(1)}) (\nabla_s \cdot \mathbf{J}_{(1')})] \delta\eta \, dS$$

surface profile (dielectric object),

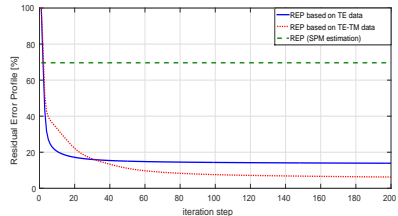
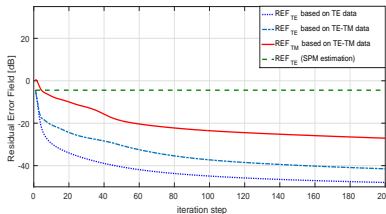
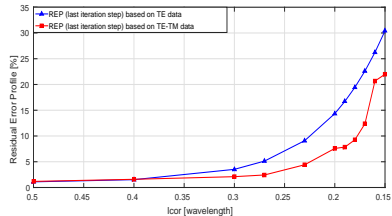
$$\delta\Phi \propto \int_S \chi [(\mathbf{E}_{(1)}^n + \mathbf{E}_{(1)}^t) \cdot (\frac{1}{1+\chi} \mathbf{E}_{(1')}^n + \mathbf{E}_{(1')}^t)] \delta\eta \, dS$$

Results

Infer surface roughness of the soil

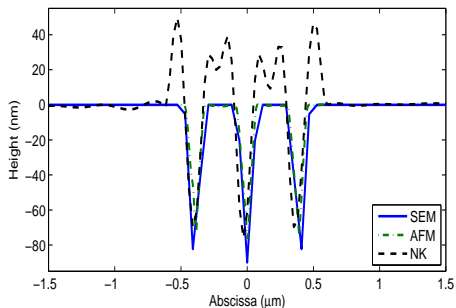
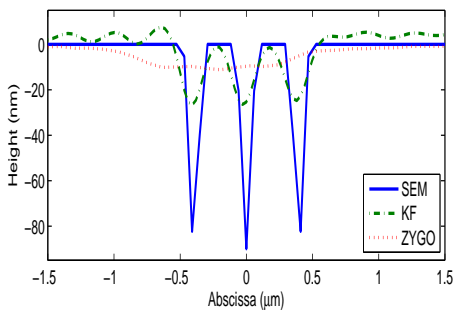


$hrms = 0.095 \lambda$, $lcor = 0.2 \lambda$



S. Arhab et al. "Inverse wave scattering of rough surfaces with emitters and receivers in the transition zone"
 Progress In Electromagnetics Research M, Vol. 45, 131–141, (2016).

$R_c = 223 \text{ nm}$



Indium phosphide surface (InP) : $\varepsilon = 12.37 + 2.11i$

S. Arhab et al. "Nanometric resolution with far-field optical profilometry" *Phys. Rev. Lett.* **111**, 053902 (2013)

THANK YOU FOR YOUR ATTENTION.